Notice of References Cited Application/Control No. | Applicant(s)/Patent Under | Reexamination | DE FERRA ET AL. | Examiner | Art Unit | Karl J. Puttlitz | 1621 | Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-4,897,355	01-1990	Eppstein et al.	424/450
	В	US-			
	С	US-			
	D	US-			
	Ε	US-			
	F	US-			
	G	US-			
	Ŧ	US-			
	1	US-			
	J	US-			
	K	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
-	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Ren et al., Tetrahedron Letters 40 (1999) 209-212			
	٧				
	w				
	×				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.